

**Search Notes**

Application/Control No.

10/617,172

Examiner

Tianjie Chen

Applicant(s)/Patent under  
Reexamination

KIM ET AL.

Art Unit

2652

**SEARCHED**

| Class   | Subclass | Date      | Examiner |
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| Updated |          | 9/30/2005 | TJ       |
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**INTERFERENCE SEARCHED**

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

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